



Deep Learning in Object Detection and Tracking

Guest Editors:

Prof. Dr. Junchi Yan

Ministry of Education Key Lab of Artificial Intelligence, Department of Computer Science and Engineering, Shanghai Jiao Tong University, Shanghai 200240, China

Dr. Minghao Guo

Department of Computer Science and Engineering, Shanghai Jiao Tong University, Shanghai 200240, China

Deadline for manuscript submissions:

closed (30 June 2023)

Message from the Guest Editors

Object detection has received great attention in recent years, its development in the past two decades can be regarded as an epitome of computer vision history. As one of the fundamental problems of computer vision, object detection forms the basis of many other computer vision tasks, such as instance segmentation, image captioning, object tracking, etc.

This Special Issue aims to discuss and solve the current key issues and problems related to object detection and tracking. In this Special Issue, original research articles and reviews are welcome. Research areas may include (but not be limited to) the following:

- Object detection and tracking;
- Few-shot/zero-shot object detection and tracking;
- Weak/semi/unsupervised object detection and tracking;
- Long-tailed object detection and tracking;
- Small object detection;
- Rotated object detection.





an Open Access Journal by MDPI

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica,
Politecnico di Milano, Piazza L.
da Vinci 32, 20133 Milano, Italy

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility: indexed within Scopus, SCIE (Web of Science), Inspec, CAPlus / SciFinder, and other databases.

Journal Rank: JCR - Q1 (Engineering, Multidisciplinary) / CiteScore - Q1 (General Engineering)

Contact Us

Applied Sciences Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland

Tel: +41 61 683 77 34
www.mdpi.com

mdpi.com/journal/applsci
applsci@mdpi.com
[X@Applsci](#)